	Application No.	Applicant(s)
Notice of Allowability	10/054,274 Examiner	HIROSE ET AL. Art Unit
	Charles Kim	2623
The MAILING DATE of this communication appears on the cover sheet with the correspondence address All claims being allowable, PROSECUTION ON THE MERITS IS (OR REMAINS) CLOSED in this application. If not included herewith (or previously mailed), a Notice of Allowance (PTOL-85) or other appropriate communication will be mailed in due course. THIS NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RIGHTS. This application is subject to withdrawal from issue at the initiative of the Office or upon petition by the applicant. See 37 CFR 1.313 and MPEP 1308.		
1. X This communication is responsive to submissions received on March 3, 2005.		
2. The allowed claim(s) is/are 1-7,9-20 (renumbered as claims 1-19 accordingly).		
3. The drawings filed on 18 January 2002 are accepted by the Examiner.		
 4. Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f). a) All b) Some* c) None of the: 1. Certified copies of the priority documents have been received. 2. Certified copies of the priority documents have been received in Application No 3. Copies of the certified copies of the priority documents have been received in this national stage application from the International Bureau (PCT Rule 17.2(a)). * Certified copies not received: 		
Applicant has THREE MONTHS FROM THE "MAILING DATE" of this communication to file a reply complying with the requirements noted below. Failure to timely comply will result in ABANDONMENT of this application. THIS THREE-MONTH PERIOD IS NOT EXTENDABLE.		
5. A SUBSTITUTE OATH OR DECLARATION must be submitted. Note the attached EXAMINER'S AMENDMENT or NOTICE OF INFORMAL PATENT APPLICATION (PTO-152) which gives reason(s) why the oath or declaration is deficient.		
6. CORRECTED DRAWINGS (as "replacement sheets") must be submitted.		
(a) ☐ including changes required by the Notice of Draftsperson's Patent Drawing Review (PTO-948) attached		
1) hereto or 2) to Paper No./Mail Date		
(b) ☐ including changes required by the attached Examiner's Amendment / Comment or in the Office action of Paper No./Mail Date		
ldentifying indicia such as the application number (see 37 CFR 1.84(c)) should be written on the drawings in the front (not the back) of each sheet. Replacement sheet(s) should be labeled as such in the header according to 37 CFR 1.121(d).		
7. DEPOSIT OF and/or INFORMATION about the deposit of BIOLOGICAL MATERIAL must be submitted. Note the attached Examiner's comment regarding REQUIREMENT FOR THE DEPOSIT OF BIOLOGICAL MATERIAL.		
 Attachment(s) 1. Notice of References Cited (PTO-892) 2. Notice of Draftperson's Patent Drawing Review (PTO-948) 3. Information Disclosure Statements (PTO-1449 or PTO/SB/O Paper No./Mail Date	6. ☐ Interview Summary Paper No./Mail Da 08), 7. ☒ Examiner's Amend	te

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DETAILED ACTION

EXAMINER'S AMENDMENT

1. An examiner's amendment to the record appears below. Should the changes and/or additions be unacceptable to applicant, an amendment may be filed as provided by 37 CFR 1.312. To ensure consideration of such an amendment, it MUST be submitted no later than the payment of the issue fee.

Authorization for this examiner's amendment was given in a telephone interview with George Yee (Registration No. 37,478) on August 4, 2005. The application has been amended as follows:

In the claims:

In claim 1, line 12, replace "region." with --region; and wherein said information of said region comprises film thickness information obtained by a film thickness measuring means.--

Cancel claim 8.

In claim 14, line 10, replace "information." with --information; and wherein said examination information comprises film thickness information obtained by an examination means comprising a film thickness measuring means.--

In claim 17, line 13, replace "information." with --information; and wherein said examination information comprises film thickness information obtained by an examination means comprising a film thickness measuring means.--

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In claim 18, line 13, replace "information." with --information; and wherein said inspection information comprises film thickness information obtained by a film thickness measuring means .--

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In claim 20, lines 12, replace "measurement information." with --measurement information; and wherein said inspection information or measurement information comprises film thickness information obtained by a test apparatus comprising a film thickness measuring means .--

Reasons for Allowance

2. The following is an examiner's statement of reasons for allowance: the essential difference from the prior art is the step of overlaying film thickness information with the whole image of the one die region. These features in combination with the other elements of the claim and the base claim are not disclosed or suggested by the prior art of record.

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

Citation of Relevant Prior Art

3. The prior art made of record and not relied upon is considered pertinent to applicant's disclosure.

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a. Miyazaki et al. U.S. Patent No. 6,016,562 discloses a method that comprises the step of overlaying defect density information with a whole image of a one die region (figure 19).

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b. Miura et al. U.S. Patent Application Publication No. 2003/0002580 discloses the step of overlaying film thickness information with a whole image of a one die region (page 8, paragraph 99). Note that the filing date of this reference prevents it from being used in a prior art rejection for the instant application.

Contact Information

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Charles Kim whose telephone number is 571-272-7421. The examiner can normally be reached on Mon thru Thurs 8:30am to 6pm and alternating Fri 9:30am to 6pm.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Jingge Wu can be reached on 571-272-7429. The fax phone number for the organization where this application or proceeding is assigned is 571-272-7414.

Information regarding the status of an application may be obtained from the Patent
Application Information Retrieval (PAIR) system. Status information for published applications
may be obtained from either Private PAIR or Public PAIR. Status information for unpublished
applications is available through Private PAIR only. For more information about the PAIR

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system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

ck

August 5, 2005

SAMIR AHMED PRIMARY EXAMINER